


<b>Search Notes</b> 	<b>Application/Control No.</b> 10622294	<b>Applicant(s)/Patent Under Reexamination</b> CHOWN, DAVID
	<b>Examiner</b> Liu, Li	<b>Art Unit</b> 2613

SEARCHED			
Class	Subclass	Date	Examiner
372	102	08/03/2006	LL
398	41-43, 152, 129, 58, 122, 125	08/03/2006, 02/08/2007	LL
385	12, 24, 93, 49	08/03/2006, 02/08/2007	LL
250	25	08/03/2006	LL

SEARCH NOTES		
Search Notes	Date	Examiner
EAST		
USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	08/03/2006, 02/08/2007, 11/27/2007, 5/31-6/13, 2008; 12/29-12/30, 2008; 6/8 & 6/9, 2009	LL
Google	08/03/2006	LL
IEEE	08/03/2006, 12/30/2008	LL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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